## Notice of References Cited

	Application/Control No. 10/708,839		Reexamination	Applicant(s)/Patent Under Reexamination BEENAU ET AL.		
	Examiner	Art Unit				
	Daniel I. Walsh	2876	Page 1 of 1			

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,725,719 A	02-1988	Oncken et al.	235/487
*	В	US-6,338,048 B1	01-2002	Mori, Toru	705/41
*	С	US-2002/0147002 A1	10-2002	Trop et al.	455/406
*	۵	US-2005/0040221 A1	02-2005	Schwarz, Charles E. JR.	235/375
*	E	US-2005/0216424 A1	09-2005	Gandre et al.	705/075
*	F	US-7,051,925 B2	05-2006	Schwarz, Jr., Charles E.	235/375
	G	US- ·			
	Н	US-			
	1	US-			
	J	US-		•	
	K	US			
	L	US-			
5 %	М	US- , ;	7		

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	. Name	Classification
	N					
	0					
	Р					
	Q					
	R			,		
	S			•		•
	Т				•	

## NON-PATENT DOCUMENTS

	_	TON 17/12/11 DOCOMENTO	,
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	Ņ		
	W		,
	×		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.